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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	3456
Number of Logic Elements/Cells	15552
Total RAM Bits	98304
Number of I/O	166
Number of Gates	661111
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	240-BFQFP Exposed Pad
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv600-4hq240i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

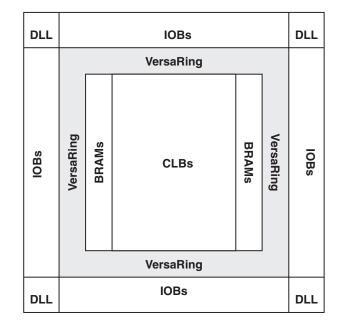


DS003-2 (v4.0) March 1, 2013

Virtex[™] 2.5 V Field Programmable Gate Arrays

Product Specification

The output buffer and all of the IOB control signals have independent polarity controls.



vao_b.eps

Figure 1: Virtex Architecture Overview

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. Two forms of over-voltage protection are provided, one that permits 5 V compliance, and one that does not. For 5 V compliance, a Zener-like structure connected to ground turns on when the output rises to approximately 6.5 V. When PCI 3.3 V compliance is required, a conventional clamp diode is connected to the output supply voltage, $V_{\rm CCO}$.

Optional pull-up and pull-down resistors and an optional weak-keeper circuit are attached to each pad. Prior to configuration, all pins not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but inputs can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins will float. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex IOBs support IEEE 1149.1-compatible boundary scan testing.

Architectural Description

Virtex Array

The Virtex user-programmable gate array, shown in Figure 1, comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

The VersaRing[™] I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Input/Output Block

The Virtex IOB, Figure 2, features SelectIO™ inputs and outputs that support a wide variety of I/O signalling standards, see Table 1.

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

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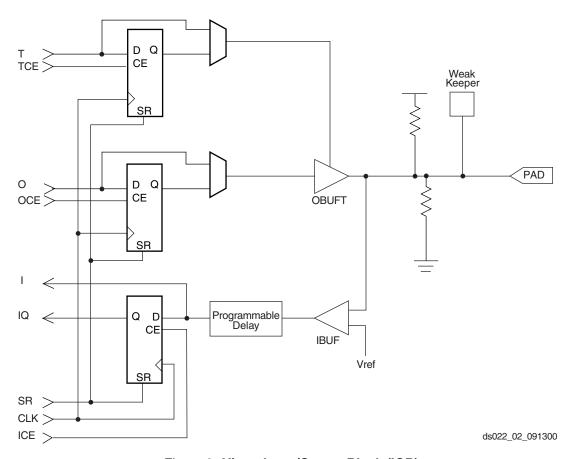


Figure 2: Virtex Input/Output Block (IOB)

Table 1: Supported Select I/O Standards

I/O Standard	Input Reference Voltage (V _{REF})	Output Source Voltage (V _{CCO})	Board Termination Voltage (V _{TT})	5 V Tolerant
LVTTL 2 – 24 mA	N/A	3.3	N/A	Yes
LVCMOS2	N/A	2.5	N/A	Yes
PCI, 5 V	N/A	3.3	N/A	Yes
PCI, 3.3 V	N/A	3.3	N/A	No
GTL	0.8	N/A	1.2	No
GTL+	1.0	N/A	1.5	No
HSTL Class I	0.75	1.5	0.75	No
HSTL Class III	0.9	1.5	1.5	No
HSTL Class IV	0.9	1.5	1.5	No
SSTL3 Class I &II	1.5	3.3	1.5	No
SSTL2 Class I & II	1.25	2.5	1.25	No
CTT	1.5	3.3	1.5	No
AGP	1.32	3.3	N/A	No



General Purpose Routing

Most Virtex signals are routed on the general purpose routing, and consequently, the majority of interconnect resources are associated with this level of the routing hierarchy. The general routing resources are located in horizontal and vertical routing channels associated with the rows and columns CLBs. The general-purpose routing resources are listed below.

- Adjacent to each CLB is a General Routing Matrix (GRM). The GRM is the switch matrix through which horizontal and vertical routing resources connect, and is also the means by which the CLB gains access to the general purpose routing.
- 24 single-length lines route GRM signals to adjacent GRMs in each of the four directions.
- 12 buffered Hex lines route GRM signals to another GRMs six-blocks away in each one of the four directions. Organized in a staggered pattern, Hex lines can be driven only at their endpoints. Hex-line signals can be accessed either at the endpoints or at the midpoint (three blocks from the source). One third of the Hex lines are bidirectional, while the remaining ones are uni-directional.

 12 Longlines are buffered, bidirectional wires that distribute signals across the device quickly and efficiently. Vertical Longlines span the full height of the device, and horizontal ones span the full width of the device.

I/O Routing

Virtex devices have additional routing resources around their periphery that form an interface between the CLB array and the IOBs. This additional routing, called the VersaRing, facilitates pin-swapping and pin-locking, such that logic redesigns can adapt to existing PCB layouts. Time-to-market is reduced, since PCBs and other system components can be manufactured while the logic design is still in progress.

Dedicated Routing

Some classes of signal require dedicated routing resources to maximize performance. In the Virtex architecture, dedicated routing resources are provided for two classes of signal.

- Horizontal routing resources are provided for on-chip 3-state busses. Four partitionable bus lines are provided per CLB row, permitting multiple busses within a row, as shown in Figure 8.
- Two dedicated nets per CLB propagate carry signals vertically to the adjacent CLB.

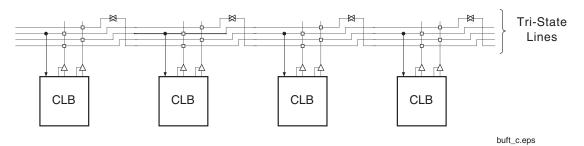


Figure 8: BUFT Connections to Dedicated Horizontal Bus Lines

Global Routing

Global Routing resources distribute clocks and other signals with very high fanout throughout the device. Virtex devices include two tiers of global routing resources referred to as primary global and secondary local clock routing resources.

• The primary global routing resources are four dedicated global nets with dedicated input pins that are designed to distribute high-fanout clock signals with minimal skew. Each global clock net can drive all CLB, IOB, and block RAM clock pins. The primary global nets can only be driven by global buffers. There are four global buffers, one for each global net. The secondary local clock routing resources consist of 24 backbone lines, 12 across the top of the chip and 12 across bottom. From these lines, up to 12 unique signals per column can be distributed via the 12 longlines in the column. These secondary resources are more flexible than the primary resources since they are not restricted to routing only to clock pins.

Clock Distribution

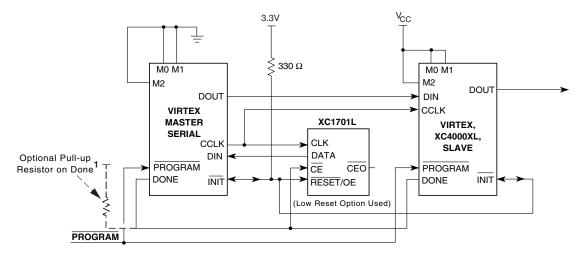
Virtex provides high-speed, low-skew clock distribution through the primary global routing resources described above. A typical clock distribution net is shown in Figure 9.

Four global buffers are provided, two at the top center of the device and two at the bottom center. These drive the four primary global nets that in turn drive any clock pin.



Table 8: Master/Slave Serial Mode Programming Switching

	Description	Figure References	Symbol	Values	Units
	DIN setup/hold, slave mode	1/2	T_{DCC}/T_{CCD}	5.0 / 0	ns, min
	DIN setup/hold, master mode	1/2	T _{DSCK} /T _{CKDS}	5.0 / 0	ns, min
	DOUT	3	T _{CCO}	12.0	ns, max
CCLK	High time	4	T _{CCH}	5.0	ns, min
OOLIK	Low time	5	T _{CCL}	5.0	ns, min
	Maximum Frequency		F _{CC}	66	MHz, max
	Frequency Tolerance, master mode with respect to nominal			+45% -30%	



Note 1: If none of the Virtex FPGAs have been selected to drive DONE, an external pull-up resistor of 330 Ω should be added to the common DONE line. (For Spartan-XL devices, add a 4.7K Ω pull-up resistor.) This pull-up is not needed if the DriveDONE attribute is set. If used, DriveDONE should be selected only for the last device in the configuration chain.

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Figure 12: Master/Slave Serial Mode Circuit Diagram

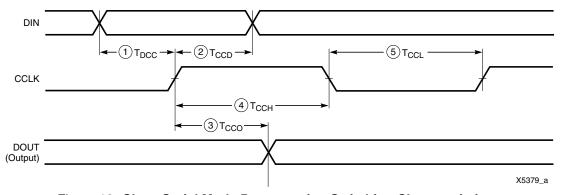


Figure 13: Slave-Serial Mode Programming Switching Characteristics



- At the rising edge of CCLK: If BUSY is Low, the data is accepted on this clock. If BUSY is High (from a previous write), the data is not accepted. Acceptance will instead occur on the first clock after BUSY goes Low, and the data must be held until this has happened.
- 4. Repeat steps 2 and 3 until all the data has been sent.
- 5. De-assert $\overline{\text{CS}}$ and $\overline{\text{WRITE}}$.

A flowchart for the write operation appears in Figure 17. Note that if CCLK is slower than f_{CCNH} , the FPGA never asserts BUSY. In this case, the above handshake is unnecessary, and data can simply be entered into the FPGA every CCLK cycle.

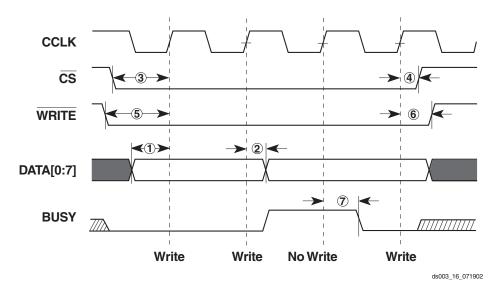


Figure 16: Write Operations



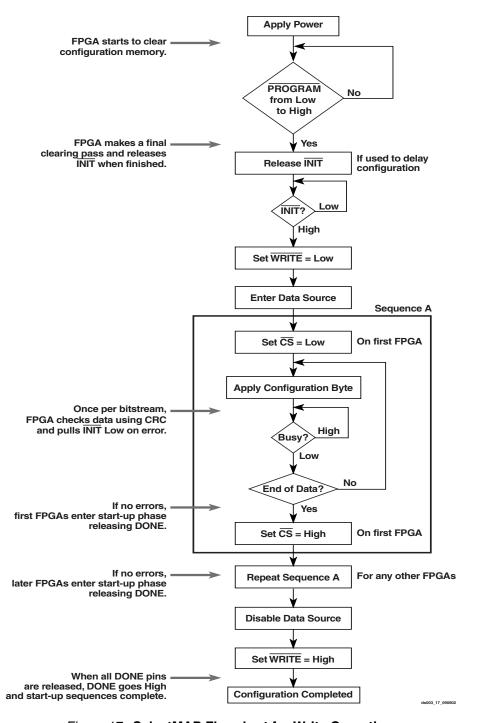


Figure 17: SelectMAP Flowchart for Write Operation

Abort

During a given assertion of $\overline{\text{CS}}$, the user cannot switch from a write to a read, or vice-versa. This action causes the current packet command to be aborted. The device will remain BUSY until the aborted operation has completed. Following an abort, data is assumed to be unaligned to word boundar-

ies, and the FPGA requires a new synchronization word prior to accepting any new packets.

To initiate an abort during a write operation, de-assert WRITE. At the rising edge of CCLK, an abort is initiated, as shown in Figure 18.



Data Stream Format

Virtex devices are configured by sequentially loading frames of data. Table 11 lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 "Virtex Configuration Architecture Advanced Users Guide".

Table 11: Virtex Bit-Stream Lengths

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138: *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.



Virtex[™] 2.5 V Field Programmable Gate Arrays

DS003-3 (v4.0) March 1, 2013

Production Product Specification

Virtex Electrical Characteristics Definition of Terms

Electrical and switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance: These speed files are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary: These speed files are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production: These speed files are released once enough production silicon of a particular device family member has been characterized to provide full correlation between speed files and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications. Contact the factory for design considerations requiring more detailed information.

Table 1 correlates the current status of each Virtex device with a corresponding speed file designation.

Table 1: Virtex Device Speed Grade Designations

	Speed	d Grade Design	ations
Device	Advance	Preliminary	Production
XCV50			-6, -5, -4
XCV100			-6, -5, -4
XCV150			-6, -5, -4
XCV200			-6, -5, -4
XCV300			-6, -5, -4
XCV400			-6, -5, -4
XCV600			-6, -5, -4
XCV800			-6, -5, -4
XCV1000			-6, -5, -4

All specifications are subject to change without notice.



Virtex DC Characteristics

Absolute Maximum Ratings

Symbol	Description ⁽¹⁾			Units
V _{CCINT}	Supply voltage relative to GND ⁽²⁾		-0.5 to 3.0	V
V _{CCO}	Supply voltage relative to GND ⁽²⁾		-0.5 to 4.0	V
V _{REF}	Input Reference Voltage	-0.5 to 3.6	V	
V	Input voltage relative to GND ⁽³⁾	Using V _{REF}	-0.5 to 3.6	V
VIN	V _{IN}	Internal threshold	-0.5 to 5.5	V
V _{TS}	Voltage applied to 3-state output		-0.5 to 5.5	V
V _{CC}	Longest Supply Voltage Rise Time from 1V-2.375V		50	ms
T _{STG}	Storage temperature (ambient)	-65 to +150	°C	
TJ	Junction temperature ⁽⁴⁾	Plastic Packages	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings can cause permanent damage to the device. These are stress
 ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions
 is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time can affect device reliability.
- 2. Power supplies can turn on in any order.
- 3. For protracted periods (e.g., longer than a day), V_{IN} should not exceed V_{CCO} by more than 3.6 V.
- 4. For soldering guidelines and thermal considerations, see the "Device Packaging" information on www.xilinx.com.

Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V _{CCINT} ⁽¹⁾	Input Supply voltage relative to GND, $T_J = 0$ °C to +85°C	Commercial	2.5 – 5%	2.5 + 5%	V
CCINT` /	Input Supply voltage relative to GND, $T_J = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$	Industrial	2.5 – 5%	2.5 + 5%	V
V _{CCO} ⁽⁴⁾	Supply voltage relative to GND, T _J = 0 °C to +85°C	Commercial	1.4	3.6	V
, CCO,	Supply voltage relative to GND, $T_J = -40^{\circ}C$ to $+100^{\circ}C$	Industrial	1.4	3.6	V
T _{IN}	Input signal transition time			250	ns

Notes:

- Correct operation is guaranteed with a minimum V_{CCINT} of 2.375 V (Nominal V_{CCINT} -5%). Below the minimum value, all delay parameters increase by 3% for each 50-mV reduction in V_{CCINT} below the specified range.
- 2. At junction temperatures above those listed as Operating Conditions, delay parameters do increase. Please refer to the TRCE report.
- 3. Input and output measurement threshold is \sim 50% of V_{CC} .
- Min and Max values for V_{CCO} are I/O Standard dependant.



DC Characteristics Over Recommended Operating Conditions

Symbol	Description	1	Device	Min	Max	Units
V _{DRINT}	Data Retention V _{CCINT} Voltage		All	2.0		V
21	(below which configuration data can be	e lost)				
V_{DRIO}	Data Retention V _{CCO} Voltage (below which configuration data can be	e lost)	All	1.2		V
I _{CCINTQ}	Quiescent V _{CCINT} supply current ^(1,3)		XCV50		50	mA
			XCV100		50	mA
			XCV150		50	mA
			XCV200		75	mA
			XCV300		75	mA
			XCV400		75	mA
			XCV600		100	mA
			XCV800		100	mA
			XCV1000		100	mA
Iccoq	Quiescent V _{CCO} supply current ⁽¹⁾		XCV50		2	mA
			XCV100		2	mA
			XCV150		2	mA
			XCV200		2	mA
			XCV300		2	mA
			XCV400		2	mA
			XCV600		2	mA
			XCV800		2	mA
			XCV1000		2	mA
I _{REF}	V _{REF} current per V _{REF} pin		All		20	μΑ
ΙL	Input or output leakage current		All	-10	+10	μΑ
C _{IN}	Input capacitance (sample tested)	BGA, PQ, HQ, packages	All		8	pF
I _{RPU}	Pad pull-up (when selected) @ V _{in} = 0 tested)	V, V _{CCO} = 3.3 V (sample	All	Note (2)	0.25	mA
I _{RPD}	Pad pull-down (when selected) @ V _{in} =	= 3.6 V (sample tested)		Note (2)	0.15	mA

Notes:

- 1. With no output current loads, no active input pull-up resistors, all I/O pins 3-stated and floating.
- 2. Internal pull-up and pull-down resistors guarantee valid logic levels at unconnected input pins. These pull-up and pull-down resistors do not guarantee valid logic levels when input pins are connected to other circuits.
- 3. Multiply I_{CCINTQ} limit by two for industrial grade.



IOB Input Switching Characteristics Standard Adjustments

			Speed Grade				
Description	Symbol	Standard ⁽¹⁾	Min	-6	-5	-4	Units
Data Input Delay Adjustments							
Standard-specific data input delay	T _{ILVTTL}	LVTTL	0	0	0	0	ns
adjustments	T _{ILVCMOS2}	LVCMOS2	-0.02	-0.04	-0.04	-0.05	ns
	T _{IPCI33_3}	PCI, 33 MHz, 3.3 V	-0.05	-0.11	-0.12	-0.14	ns
	T _{IPCI33_5}	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns
	T _{IPCI66_3}	PCI, 66 MHz, 3.3 V	-0.05	-0.11	-0.12	-0.14	ns
	T _{IGTL}	GTL	0.10	0.20	0.23	0.26	ns
	T _{IGTLP}	GTL+	0.06	0.11	0.12	0.14	ns
	T _{IHSTL}	HSTL	0.02	0.03	0.03	0.04	ns
	T _{ISSTL2}	SSTL2	-0.04	-0.08	-0.09	-0.10	ns
	T _{ISSTL3}	SSTL3	-0.02	-0.04	-0.05	-0.06	ns
	T _{ICTT}	CTT	0.01	0.02	0.02	0.02	ns
	T _{IAGP}	AGP	-0.03	-0.06	-0.07	-0.08	ns

Notes:

IOB Output Switching Characteristics

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays with the values shown in **IOB Output Switching Characteristics Standard Adjustments**, page 9.

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Propagation Delays						
O input to Pad	T _{IOOP}	1.2	2.9	3.2	3.5	ns, max
O input to Pad via transparent latch	T _{IOOLP}	1.4	3.4	3.7	4.0	ns, max
3-State Delays		·				
T input to Pad high-impedance ⁽¹⁾	T _{IOTHZ}	1.0	2.0	2.2	2.4	ns, max
T input to valid data on Pad	T _{IOTON}	1.4	3.1	3.3	3.7	ns, max
T input to Pad high-impedance via transparent latch ⁽¹⁾	T _{IOTLPHZ}	1.2	2.4	2.6	3.0	ns, max
T input to valid data on Pad via transparent latch	T _{IOTLPON}	1.6	3.5	3.8	4.2	ns, max
GTS to Pad high impedance ⁽¹⁾	T _{GTS}	2.5	4.9	5.5	6.3	ns, max
Sequential Delays			1	1		,
Clock CLK						
Minimum Pulse Width, High	T _{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{CL}	0.8	1.5	1.7	2.0	ns, min

^{1.} Input timing for LVTTL is measured at 1.4 V. For other I/O standards, see Table 3.



Block RAM Switching Characteristics

	Speed Grade					
Description	Symbol	Min	-6	-5	-4	Units
Sequential Delays						
Clock CLK to DOUT output	T _{BCKO}	1.7	3.4	3.8	4.3	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾		Setu	p Time / H	old Time		
ADDR inputs	T _{BACK} /T _{BCKA}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
DIN inputs	T _{BDCK} /T _{BCKD}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
EN input	T _{BECK} /T _{BCKE}	1.3 / 0	2.6 / 0	3.0 / 0	3.4 / 0	ns, min
RST input	T _{BRCK} /T _{BCKR}	1.3 / 0	2.5 / 0	2.7 / 0	3.2 / 0	ns, min
WEN input	T _{BWCK} /T _{BCKW}	1.2 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{BPWH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{BPWL}	0.8	1.5	1.7	2.0	ns, min
CLKA -> CLKB setup time for different ports	T _{BCCS}		3.0	3.5	4.0	ns, min

Notes:

TBUF Switching Characteristics

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Combinatorial Delays						
IN input to OUT output	T _{IO}	0	0	0	0	ns, max
TRI input to OUT output high-impedance	T _{OFF}	0.05	0.09	0.10	0.11	ns, max
TRI input to valid data on OUT output	T _{ON}	0.05	0.09	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

		Speed Grade			
Description	Symbol	-6	-5	-4	Units
TMS and TDI Setup times before TCK	T _{TAPTCK}	4.0	4.0	4.0	ns, min
TMS and TDI Hold times after TCK	T _{TCKTAP}	2.0	2.0	2.0	ns, min
Output delay from clock TCK to output TDO	T _{TCKTDO}	11.0	11.0	11.0	ns, max
Maximum TCK clock frequency	F _{TCK}	33	33	33	MHz, max

^{1.} A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Minimum Clock-to-Out for Virtex Devices

	With DLL	Without DLL									
I/O Standard	All Devices	V50	V100	V150	V200	V300	V400	V600	V800	V1000	Units
*LVTTL_S2	5.2	6.0	6.0	6.0	6.0	6.1	6.1	6.1	6.1	6.1	ns
*LVTTL_S4	3.5	4.3	4.3	4.3	4.3	4.4	4.4	4.4	4.4	4.4	ns
*LVTTL_S6	2.8	3.6	3.6	3.6	3.6	3.7	3.7	3.7	3.7	3.7	ns
*LVTTL_S8	2.2	3.1	3.1	3.1	3.1	3.1	3.1	3.2	3.2	3.2	ns
*LVTTL_S12	2.0	2.9	2.9	2.9	2.9	2.9	2.9	3.0	3.0	3.0	ns
*LVTTL_S16	1.9	2.8	2.8	2.8	2.8	2.8	2.8	2.9	2.9	2.9	ns
*LVTTL_S24	1.8	2.6	2.6	2.7	2.7	2.7	2.7	2.7	2.7	2.8	ns
*LVTTL_F2	2.9	3.8	3.8	3.8	3.8	3.8	3.8	3.9	3.9	3.9	ns
*LVTTL_F4	1.7	2.6	2.6	2.6	2.6	2.6	2.6	2.7	2.7	2.7	ns
*LVTTL_F6	1.2	2.0	2.0	2.0	2.1	2.1	2.1	2.1	2.1	2.2	ns
*LVTTL_F8	1.1	1.9	1.9	1.9	1.9	2.0	2.0	2.0	2.0	2.0	ns
*LVTTL_F12	1.0	1.8	1.8	1.8	1.8	1.9	1.9	1.9	1.9	1.9	ns
*LVTTL_F16	0.9	1.7	1.8	1.8	1.8	1.8	1.8	1.8	1.9	1.9	ns
*LVTTL_F24	0.9	1.7	1.7	1.7	1.8	1.8	1.8	1.8	1.8	1.9	ns
LVCMOS2	1.1	1.9	1.9	1.9	2.0	2.0	2.0	2.0	2.0	2.1	ns
PCI33_3	1.5	2.4	2.4	2.4	2.4	2.4	2.4	2.5	2.5	2.5	ns
PCI33_5	1.4	2.2	2.2	2.3	2.3	2.3	2.3	2.3	2.3	2.4	ns
PCI66_3	1.1	1.9	1.9	2.0	2.0	2.0	2.0	2.0	2.1	2.1	ns
GTL	1.6	2.5	2.5	2.5	2.5	2.5	2.5	2.6	2.6	2.6	ns
GTL+	1.7	2.5	2.5	2.6	2.6	2.6	2.6	2.6	2.6	2.7	ns
HSTL I	1.1	1.9	1.9	1.9	1.9	2.0	2.0	2.0	2.0	2.0	ns
HSTL III	0.9	1.7	1.7	1.8	1.8	1.8	1.8	1.8	1.8	1.9	ns
HSTL IV	0.8	1.6	1.6	1.6	1.7	1.7	1.7	1.7	1.7	1.8	ns
SSTL2 I	0.9	1.7	1.7	1.7	1.7	1.8	1.8	1.8	1.8	1.8	ns
SSTL2 II	0.8	1.6	1.6	1.6	1.6	1.7	1.7	1.7	1.7	1.7	ns
SSTL3 I	0.8	1.6	1.7	1.7	1.7	1.7	1.7	1.7	1.8	1.8	ns
SSTL3 II	0.7	1.5	1.5	1.6	1.6	1.6	1.6	1.6	1.6	1.7	ns
CTT	1.0	1.8	1.8	1.8	1.9	1.9	1.9	1.9	1.9	2.0	ns
AGP	1.0	1.8	1.8	1.9	1.9	1.9	1.9	1.9	1.9	2.0	ns

^{*}S = Slow Slew Rate, F = Fast Slew Rate

Notes:

^{1.} Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

^{2.} Input and output timing is measured at 1.4 V for LVTTL. For other I/O standards, see Table 3. In all cases, an 8 pF external capacitive load is used.



Virtex Pinout Information

Pinout Tables

See www.xilinx.com for updates or additional pinout information. For convenience, Table 2, Table 3 and Table 4 list the locations of special-purpose and power-supply pins. Pins not listed are either user I/Os or not connected, depending on the device/package combination. See the Pinout Diagrams starting on page 17 for any pins not listed for a particular part/package combination.

Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages)

Pin Name	Device	CS144	TQ144	PQ/HQ240
GCK0	All	K7	90	92
GCK1	All	M7	93	89
GCK2	All	A7	19	210
GCK3	All	A6	16	213
MO	All	M1	110	60
M1	All	L2	112	58
M2	All	N2	108	62
CCLK	All	B13	38	179
PROGRAM	All	L12	72	122
DONE	All	M12	74	120
INIT	All	L13	71	123
BUSY/DOUT	All	C11	39	178
D0/DIN	All	C12	40	177
D1	All	E10	45	167
D2	All	E12	47	163
D3	All	F11	51	156
D4	All	H12	59	145
D5	All	J13	63	138
D6	All	J11	65	134
D7	All	K10	70	124
WRITE	All	C10	32	185
CS	All	D10	33	184
TDI	All	A11	34	183
TDO	All	A12	36	181
TMS	All	B1	143	2
TCK	All	C3	2	239
V _{CCINT}	All	A9, B6, C5, G3, G12, M5, M9, N6	10, 15, 25, 57, 84, 94, 99, 126	16, 32, 43, 77, 88, 104, 137, 148, 164, 198, 214, 225



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V _{CCO}	All	Banks 0 and 1: A2, A13, D7 Banks 2 and 3: B12, G11, M13 Banks 4 and 5: N1, N7, N13 Banks 6 and 7: B2, G2, M2	No I/O Banks in this package: 1, 17, 37, 55, 73, 92, 109, 128	No I/O Banks in this package: 15, 30, 44, 61, 76, 90, 105, 121, 136, 150, 165, 180, 197, 212, 226, 240
V _{RFF} Bank 0	XCV50	C4, D6	5, 13	218, 232
(V _{REF} pins are listed	XCV100/150	+ B4	+ 7	+ 229
incrementally. Connect	XCV200/300	N/A	N/A	+ 236
all pins listed for both the required device	XCV400	N/A	N/A	+ 215
and all smaller devices	XCV600	N/A	N/A	+ 230
listed in the same package.)	XCV800	N/A	N/A	+ 222
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 1	XCV50	A10, B8	22, 30	191, 205
(V _{REF} pins are listed	XCV100/150	+ D9	+ 28	+ 194
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 187
the required device	XCV400	N/A	N/A	+ 208
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 193
package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV800	N/A	N/A	+ 201
V _{REF} , Bank 2	XCV50	D11, F10	42, 50	157, 171
(V _{REF} pins are listed	XCV100/150	+ D13	+ 44	+ 168
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 175
the required device	XCV400	N/A	N/A	+ 154
and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV600	N/A	N/A	+ 169
	XCV800	N/A	N/A	+ 161



Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V _{REF} , Bank 3	XCV50	M18, V20	N/A	N/A	N/A
(V _{REF} pins are listed	XCV100/150	+ R19	R4, V4, Y3	N/A	N/A
incrementally. Connect all pins listed for both the required device and all	XCV200/300	+ P18	+ AC2	V2, AB4, AD4, AF3	N/A
smaller devices listed in the	XCV400	N/A	N/A	+ U2	V4, W5,
same package.)					AD3, AE5, AK2
Within each bank, if input reference voltage is not	XCV600	N/A	N/A	+ AC3	+ AF1
required, all V _{REF} pins are	XCV800	N/A	N/A	+ Y3	+ AA4
general I/O.	XCV1000	N/A	N/A	N/A	+ AH4
V _{REF} , Bank 4	XCV50	V12, Y18	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect all	XCV100/150	+ W15	AC12, AE5, AE8,	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ V14	+ AE4	AJ7, AL4, AL8, AL13	N/A
same package.) Within each bank, if input reference voltage is not	XCV400	N/A	N/A	+ AK15	AL7, AL10, AL16, AM4, AM14
required, all V _{REF} pins are	XCV600	N/A	N/A	+ AK8	+ AL9
general I/O.	XCV800	N/A	N/A	+ AJ12	+ AK13
	XCV1000	N/A	N/A	N/A	+ AN3
V _{REF} , Bank 5	XCV50	V9, Y3	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect all pins listed for both the	XCV100/150	+ W6	AC15, AC18, AD20	N/A	N/A
required device and all smaller devices listed in the	XCV200/300	+ V7	+ AE23	AJ18, AJ25, AK23, AK27	N/A
within each bank, if input reference voltage is not	XCV400	N/A	N/A	+ AJ17	AJ18, AJ25, AL20, AL24, AL29
required, all V _{REF} pins are general I/O.	XCV600	N/A	N/A	+ AL24	+ AM26
	XCV800	N/A	N/A	+ AH19	+ AN23
	XCV1000	N/A	N/A	N/A	+ AK28
V _{REF} , Bank 6	XCV50	M2, R3	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect all	XCV100/150	+ T1	R24, Y26, AA25,	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ T3	+ AD26	V28, AB28, AE30, AF28	N/A
same package.) Within each bank, if input	XCV400	N/A	N/A	+ U28	V29, Y32, AD31, AE29, AK32
reference voltage is not	XCV600	N/A	N/A	+ AC28	+ AE31
required, all V _{REF} pins are general I/O.	XCV800	N/A	N/A	+ Y30	+ AA30
general I/O.	XCV1000	N/A	N/A	N/A	+ AH30

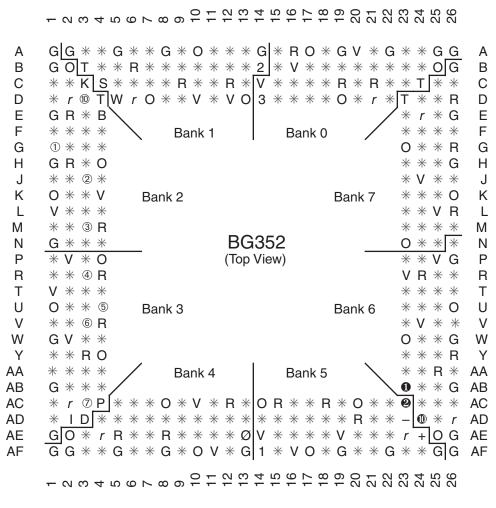


Table 4: Virtex Pinout Tables (Fine-Pitch BGA)

Pin Name	Device	FG256	FG456	FG676	FG680
GCK0	All	N8	W12	AA14	AW19
GCK1	All	R8	Y11	AB13	AU22
GCK2	All	C9	A11	C13	D21
GCK3	All	B8	C11	E13	A20
M0	All	N3	AB2	AD4	AT37
M1	All	P2	U5	W7	AU38
M2	All	R3	Y4	AB6	AT35
CCLK	All	D15	B22	D24	E4
PROGRAM	All	P15	W20	AA22	AT5
DONE	All	R14	Y19	AB21	AU5
INIT	All	N15	V19	Y21	AU2
BUSY/DOUT	All	C15	C21	E23	E3
D0/DIN	All	D14	D20	F22	C2
D1	All	E16	H22	K24	P4
D2	All	F15	H20	K22	P3
D3	All	G16	K20	M22	R1
D4	All	J16	N22	R24	AD3
D5	All	M16	R21	U23	AG2
D6	All	N16	T22	V24	AH1
D7	All	N14	Y21	AB23	AR4
WRITE	All	C13	A20	C22	B4
CS	All	B13	C19	E21	D5
TDI	All	A15	B20	D22	В3
TDO	All	B14	A21	C23	C4
TMS	All	D3	D3	F5	E36
TCK	All	C4	C4	E6	C36
DXN	All	R4	Y5	AB7	AV37
DXP	All	P4	V6	Y8	AU35



BG352 Pin Function Diagram



DS003_19_100600

Figure 5: BG352 Pin Function Diagram



FG256 Pin Function Diagram

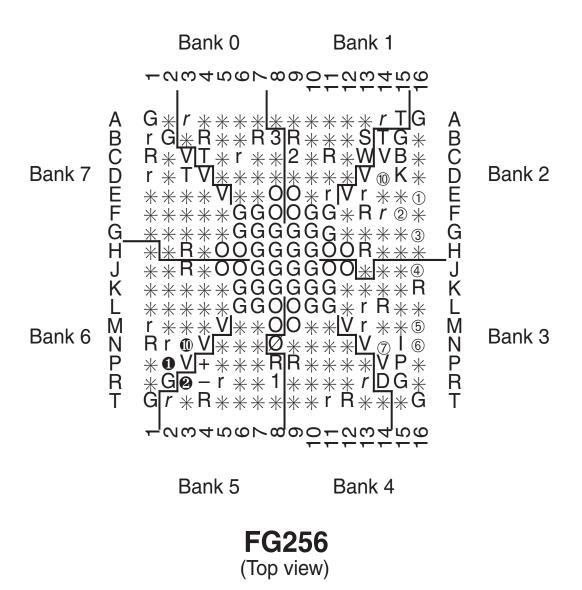


Figure 8: FG256 Pin Function Diagram



FG680 Pin Function Diagram

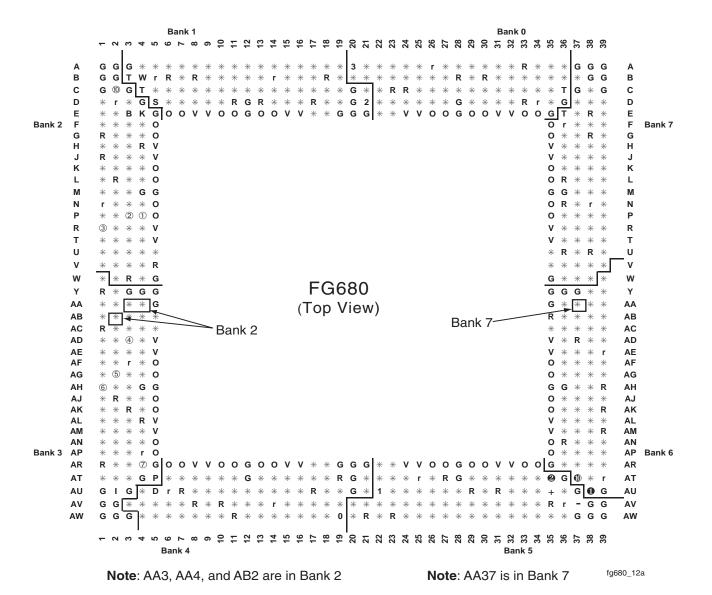


Figure 11: FG680 Pin Function Diagram